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Supporting Information

Ferrocene-diketopyrrolopyrrole based non-fullerene acceptors for bulk heterojunction polymer solar cells

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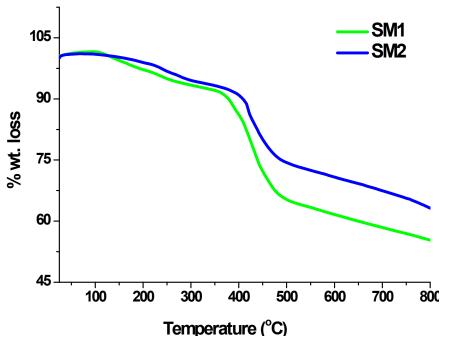


Fig. S1 Thermogravimetric analysis of **SM1** and **SM2** measured at a heating rate of 10 °C/min under nitrogen atmosphere.

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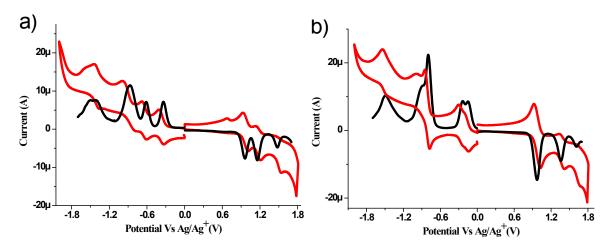


Fig. S2 CV (red line) and DPV (black line) plots of (a) SM1 and (b) SM2.

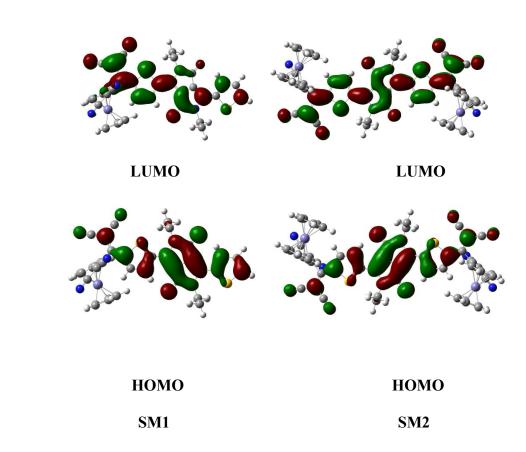


Fig. S3 The frontier molecular orbitals of SM1 and SM2 at B3LYP/6-31G(d) level.

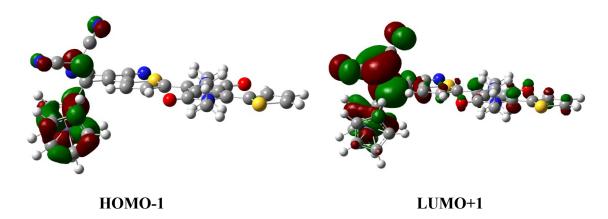


Fig. S4 The frontier molecular orbitals of SM1 at B3LYP/6-31G(d) level.

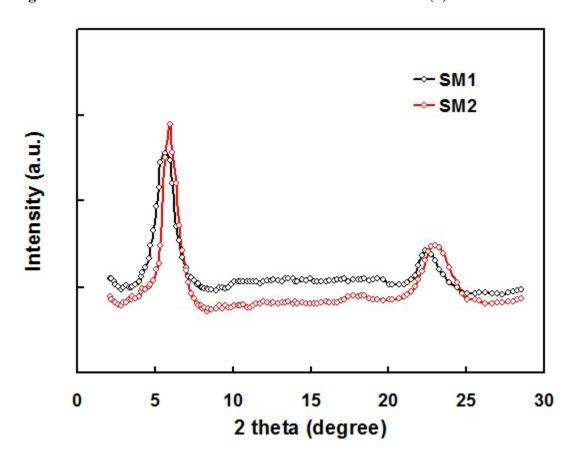


Fig. S5 XRD patterns of the SM1 and SM2 thin films.

Table S1. Calculated major electronic transitions for SM1 and SM2 in the gas phase.

	Wavelength (nm)	Composition	Assignment	f^{a}
SM1	672	HOMO→LUMO (0.60)	$\pi^-\pi^*$ transition	0.51
SM1	662	HOMO→LUMO (0.37)	π–π* transition	0.20
		HOMO-1→LUMO+1 (0.38)		
SM2	735	HOMO→LUMO (0.70)	π - π * transition	1.07

fa= Oscillation Strength

Table S2 Photovoltaic properties of the devices based on as cast and DIO (3v%) additive **P:SM1** (1:2) and **P:SM2** (1:2) active layers

Active layers	$J_{\rm sc}~({\rm mA/cm^2})$	V _{oc} (V)	FF	PCE (%)
P:SM1 (as cst)	6.23	1.02	0.38	2.41
P:SM2 (as cast)	7.05	0.91	0.41	2.66
P:SM1 (DIO additive)	8.81	0.98	0.49	4.23
P:SM2 (DIO additive)	9.68	0.88	0.52	4.88

Experimental Section:

The UV-visible absorption spectra of DPPs were recorded on UV-visible Spectrophotometer in dichloromethane. The TGA analyses were performed on the thermal analysis system at the heating rate of 10 °C per minute under a nitrogen atmosphere. Cyclic voltammograms (CVs) and

differential voltammograms (DPVs) were recorded in dichloromethane solvent using 0.1 M tetrabutylammonium hexafluorophosphate (Bu_4NPF_6) as supporting electrolyte on an electrochemical analyzer using glassy carbon as working electrode, Pt wire as the counter electrode, and saturated Ag/Ag^+ as the reference electrode.

$$\begin{array}{c} C_{10}H_{21} \\ C_{10}H_{21} \\$$

Scheme S1. Synthesis of TCBD based DPPs SM1 and SM2.

Synthesis of SM1:

In 50 ml round bottom flask DPP **5** (0.100 g, 0.13 mmol) and TCNE (0.018 g, 0.14 mmol) were dissolved in dichloromethane (15 ml) under argon atmosphere. The reaction mixture was stirred at room temperature for 5 hours. The solvent was removed under vacuo and the product was purified by silica-column chromatography with hexane: dichloromethane (1:1) as an eluent to yield **SM1** as a dark blue colored solid in 91% yield.

Synthesis of SM2:

In 50 ml round bottom flask DPP 6 (0.100 g, 0.10 mmol) and TCNE (0.026 g, 0.20 mmol) were dissolved in dichloromethane (15 ml) under argon atmosphere. The reaction mixture was stirred

at room temperature for 5 hours. The solvent was removed under vacuo and the product was purified by silica-column chromatography with hexane: dichloromethane (2:1) as an eluent to yield 95% **SM2** as a dark green colored solid.

Device fabrication

The PSCs were fabricated with a configuration of ITO/ PEDOT:PSS (40 nm)/P:SM1 or SM2/PFN/Al. Firstly, indium tin oxide coated glass substrates were cleaned with detergent powder solution and then ultrasonicated in deionized water, acetone and isopropyl alcohol sequentially for 15 min each and then dried in vacuum oven for 2 hr at 50° C. A thin layer of PEDOT:PSS was deposited through spin-coating on pre-cleaned ITO-coated glass substrate from a PEDOT:PSS aqueous solution (Baytron P VP AI 4083) at 2000 rpm and dried subsequently at 120 °C for 15 min in air. The active layer solution was prepared by mixing P and SM1 or SM2 in different weight ratio from 1:1 to 1:2.5 in THF solution with total concentration of 16 mg/mL and spun cast on the top of PEDOT:PSS film at 1500 rpm for 30s. For solvent additive, different concentration of DIO was added to the host THF solution and then the solution was stirred overnight on a hot plate at 120 °C. The warm solution was spun on the top of PEDOT:PSS film at 1500 rpm for 30 s. After the films were (i) either transferred to vacuum oven immediately for slow vacuum drying at room temperature for 2 hr or (ii) thermally annealed at 110 °C for 2 min. Then methanol solution of PFN at a concentration of 1.0 mg/ mL was deposited on the top the active layer at 3000 rpm for 30 s to afford a thickness of 15 nm. Finally, top Al electrode was deposited in vacuum onto the cathode buffer layer at a pressure of $\approx 1.0 \times 10^{-5}$ Pa. The active area of the device was 10 mm². We have fabricated four devices in one substrate. The current-voltage (J-V) characteristics of the PSCs were measured on a computer controlled Keithley 2450 Source meter. Solar Simulator with a 450 W xenon lamp and an air mass (AM) 1.5 filter was used as the light source. The light intensity was kept constant at 100 mW/cm². The IPCE of the devices was measured at illuminating the device through the light source and monochromator and the resulting current was measured using a Keithley electrometer under short circuit condition. All the measurements were done in ambient condition without encapsulating the devices.

TDDFT Data

Calculation method:

B3LYP/6-31+G** for C, H, N, O, S, and Lanl2DZ for Fe with Gaussian 09 [1].

Excitation energies and oscillator strengths:

1:

For SM1

```
Excited State
                      Singlet-A
                                     1.8076 eV 685.92 nm f=0.0010
\langle S**2 \rangle = 0.000
     171 ->174
                      0.17131
    171 ->175
                      0.49707
                     -0.10957
    171 ->176
    171 ->179
                      0.35595
    172 ->178
                      0.24610
This state for optimization and/or second-order correction.
Total Energy, E(TD-HF/TD-KS) = -2784.88234257
Copying the excited state density for this state as the 1-particle RhoCI
density.
Excited State
                2:
                        Singlet-A
                                       1.8456 eV 671.79 nm f=0.5106
<s**2>=0.000
     171 ->178
                      0.13341
    172 ->174
                     -0.10388
    172 ->175
                     -0.23952
    172 ->179
                     -0.18922
    173 ->174
                      0.60375
                     -0.10494
    173 <-174
                3:
Excited State
                        Singlet-A
                                    1.8739 eV 661.64 nm f=0.2008
<S**2>=0.000
                     -0.23384
    171 ->178
    172 ->174
                      0.19879
    172 ->175
                      0.37688
    172 ->179
                      0.31798
    173 ->174
                      0.36503
                                       2.0910 eV 592.93 nm f=0.0005
Excited State
                4:
                        Singlet-A
<S**2>=0.000
    171 ->178
                      0.11455
    172 ->174
                      0.66504
    172 ->175
                     -0.12685
    172 ->176
                      0.10087
    172 ->179
                     -0.11863
Excited State
                5:
                        Singlet-A
                                       2.1678 eV 571.93 nm f=0.0013
<S**2>=0.000
     171 ->174
                      0.67676
                     -0.10672
    172 ->178
Excited State
               6:
                        Singlet-A 2.2585 eV 548.97 nm f=0.0393
<s**2>=0.000
```

173 ->175 0.69450

For SM2

```
Excited State 1: Singlet-A 1.6871 \text{ eV} 734.88 \text{ nm} f=1.0714
< S**2>=0.000
                    0.70456
    253 -> 254
    253 <- 254
                    -0.12709
This state for optimization and/or second-order correction.
Total Energy, E(TD-HF/TD-KS) = -3817.95121639
Copying the excited state density for this state as the 1-particle RhoCI
density.
Excited State 2: Singlet-A 1.7459 eV 710.13 nm f=0.0114
< S * * 2 > = 0.000
    251 -> 254
                    0.61586
    251 -> 255
                    0.17163
    251 -> 256
                    -0.11147
    251 -> 262
                    0.10482
    252 -> 254
                   -0.18876
Excited State 3:
                     Singlet-A 1.7507 eV 708.20 nm f=0.0158
< S**2 >= 0.000
    251 -> 254
                    0.18618
    252 -> 254
                    0.62759
    252 -> 255
                    -0.15906
    252 -> 256
                   -0.10477
                     Singlet-A 1.7620 eV 703.66 nm f=0.0008
Excited State 4:
< S**2 >= 0.000
    249 -> 254
                    0.39706
    249 -> 255
                    0.20753
    249 -> 256
                   -0.29559
    249 -> 257
                    0.26659
    249 -> 262
                    0.23177
    249 -> 263
                    0.13810
    251 -> 260
                  -0.19076
Excited State 5:
                    Singlet-A 1.7706 eV 700.22 nm f=0.0007
< S**2 >= 0.000
    250 -> 254
                    0.39048
    250 -> 255
                    -0.18462
    250 -> 256
                    -0.30798
    250 -> 257
                    -0.27414
    250 -> 262
                    0.15364
    250 -> 263
                   -0.23028
    252 -> 261
                    0.19414
Excited State 6: Singlet-A 1.8699 eV 663.06 nm f=0.0015
< S**2 >= 0.000
    250 -> 254
                   0.47629
    250 -> 256
                    0.15688
    250 -> 257
                    0.16716
```

250	->	261	-0.13473
250	->	263	0.13134
252	->	254	-0.13762
252	->	256	-0.19937
252	->	257	-0.19207
252	->	261	-0.12304
252	->	262	0.10466
252	->	263	-0.15704

Reference

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